

<b>Notice of References Cited</b>	Application/Control No. 10/562,420		Applicant(s)/Patent Under Reexamination TAKANO ET AL.	
	Examiner JOHN B. STREGE		Art Unit 2624	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0053663	03-2003	Chen et al.	382/117
*	B	US-7,146,983	12-2006	Hohla et al.	128/898
*	C	US-5,495,338	02-1996	Gouriou et al.	356/402
*	D	US-7,123,753	10-2006	Takahashi et al.	382/117
*	E	US-7,079,158	07-2006	Lambertsen, Kirsten	345/630
*	F	US-6,937,755	08-2005	Orpaz et al.	382/162
*	G	US-6,091,836	07-2000	Takano et al.	382/118
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.